TOSHIBA Field Effect Transistor Silicon N Channel MOS Type

# SSM3K02T

# **High Speed Switching Applications**

Unit: mm

• Small package

• Low on resistance:  $R_{on}$  = 200 m $\Omega$  (max) (VGS = 4 V) :  $R_{on}$  = 250 m $\Omega$  (max) (VGS = 2.5 V)

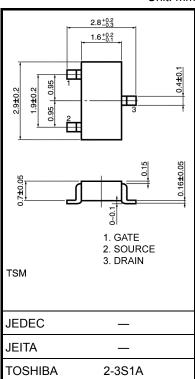
• Low gate threshold voltage:  $V_{th} = 0.6 \sim 1.1 \text{ V (V}_{DS} = 3 \text{ V, I}_{D} = 0.1 \text{ mA)}$ 

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## Absolute Maximum Ratings (Ta = 25°C)

| Characteristi                       | cs    | Symbol                     | Rating         | Unit |  |
|-------------------------------------|-------|----------------------------|----------------|------|--|
| Drain-source voltage                |       | $V_{DS}$                   | 30             | V    |  |
| Gate-source voltage                 |       | $V_{GSS}$                  | ±10            | V    |  |
| Drain current                       | DC    | I <sub>D</sub>             | 2.5            | Α    |  |
|                                     | Pulse | I <sub>DP</sub>            | 5.0            |      |  |
| Drain power dissipation (Ta = 25°C) |       | P <sub>D</sub><br>(Note 1) | 1250           | mW   |  |
| Channel temperature                 |       | T <sub>ch</sub>            | 150            | °C   |  |
| Storage temperature range           |       | T <sub>stg</sub>           | <b>−55~150</b> | °C   |  |

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e.



Weight: 0.01 g (typ.)

operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

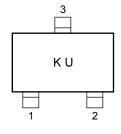
Note 1: Mounted on FR4 board

 $(25.4 \text{ mm} \times 25.4 \text{ mm} \times 1.6 \text{ t}, \text{ Cu pad: } 645 \text{ mm}^2, \text{ t} = 10 \text{ s})$ 

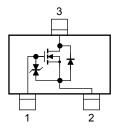
Note 2: The pulse width limited by max channel temperature.

#### Marking

Note:



#### **Equivalent Circuit**



# **Handling Precaution**

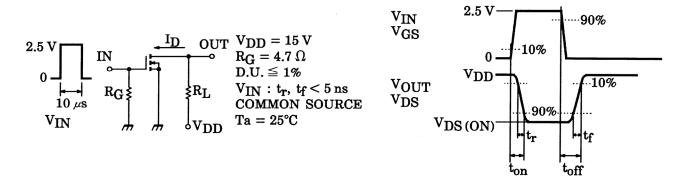
When handling individual devices (which are not yet mounted on a circuit board), be sure that the environment is protected against electrostatic electricity. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.

## **Electrical Characteristics (Ta = 25°C)**

| Chara                      | cteristics   | Symbol               | Test Condition   |        | Min | Тур. | Max | Unit |
|----------------------------|--|----------------------|--|--------|-----|------|-----|------|
| Gate leakage curr          | ent  | I <sub>GSS</sub>     | $V_{GS} = \pm 10 \text{ V}, V_{DS} = 0$  |        | _   | _    | ±5  | μА   |
| Drain-source brea          | kdown voltage  | V (BR) DSS           | $I_D = 1$ mA, $V_{GS} = 0$   |        | 30  | _    | _   | V    |
| Drain cut-off curre        | nt   | I <sub>DSS</sub>     | V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0  |        | _   | _    | 1   | μА   |
| Gate threshold vo          | Itage  | $V_{th}$             | $V_{DS} = 3 \text{ V}, I_{D} = 0.1 \text{ mA}$   |        | 0.6 | _    | 1.1 | V    |
| Forward transfer a         | admittance   | Y <sub>fs</sub>      | V <sub>DS</sub> = 3 V, I <sub>D</sub> = 1.25 A   | (Note) | 2.2 | _    | _   | S    |
| Drain-source ON resistance |  | R <sub>DS (ON)</sub> | I <sub>D</sub> = 1.25 A, V <sub>GS</sub> = 4 V   | (Note) | _   | 140  | 200 | - mΩ |
|                            |  |                      | I <sub>D</sub> = 1.25 A, V <sub>GS</sub> = 2.5 V   | (Note) | _   | 180  | 250 |      |
| Input capacitance          | capacitance $C_{iss}$ $V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$               |                      |  | _      | 115 | _    | pF  |      |
| Reverse transfer of        | erse transfer capacitance $C_{rss}$ $V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$ |                      |  | _      | 24  | _    | pF  |      |
| Output capacitance C       |  | C <sub>oss</sub>     | V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0, f = 1 MHz                                   |        | _   | 60   | _   | pF   |
| Switching time             | Turn-on time   | t <sub>on</sub>      | $V_{DD} = 15 \text{ V}, I_D = 0.5 \text{ A}, V_{GS} = 0~2.5 \text{ V}, R_G = 4.7 \Omega$ |        | _   | 52   | _   | ne   |
|                            | Turn-off time  | t <sub>off</sub>     |  | _      | 80  | _    | ns  |      |

Note: Pulse test

## **Switching Time Test Circuit**

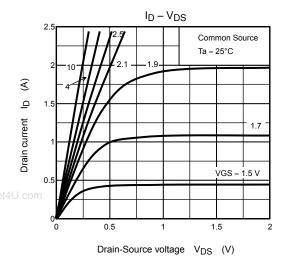


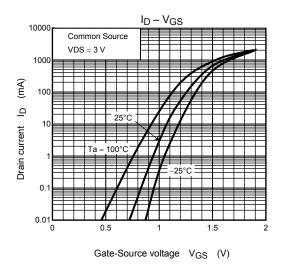
## **Precaution**

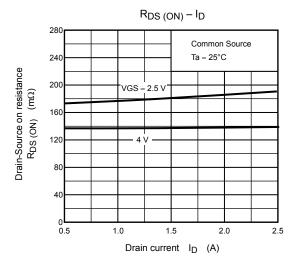
 $V_{th}$  can be expressed as voltage between gate and source when low operating current value is ID = 100  $\mu$ A for this product. For normal switching operation, VGS (ON) requires higher voltage than  $V_{th}$  and VGS (off) requires lower voltage than  $V_{th}$ .

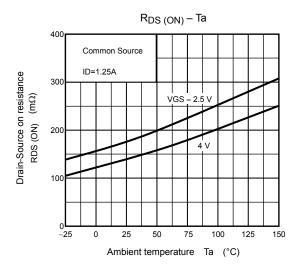
(Relationship can be established as follows:  $V_{GS}$  (off)  $< V_{th} < V_{GS}$  (ON))

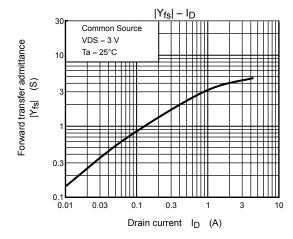
Please take this into consideration for using the device.

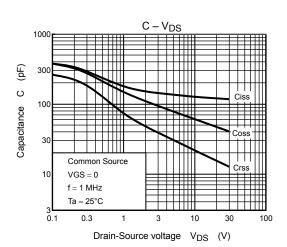




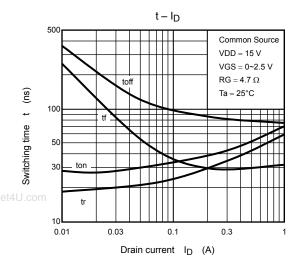


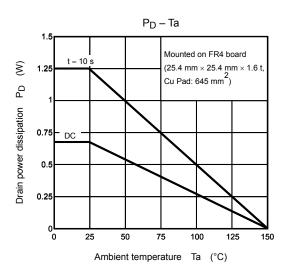


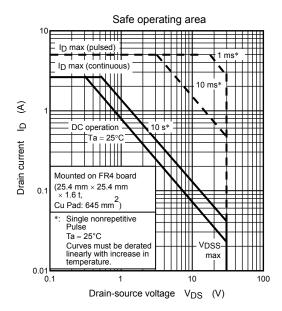


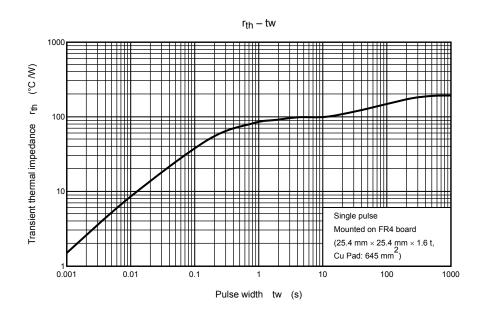


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